

FORM PTO 1449 (modified)

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2004\_1604ASERIAL NO.  
NEW 10/511751U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)  
(Use several sheets if necessary)

Date Submitted to PTO: October 19, 2004

APPLICANT  
Takuji MAEDA et al.FILING DATE  
October 19, 2004GROUP  
2134

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
/Y.B./	AG	8-190529	7/1996	JP			Abstract
/Y.B./	AH	2000-242491	9/2000	JP			Abstract
/Y.B./	AI	2002-091772	3/2002	JP			Abstract
/Y.B./	AJ	2000-311083	11/2000	JP			Abstract
/Y.B./	AK	2-122330	5/1990	JP			Abstract
/Y.B./	AL	7-295800	11/1995	JP			Abstract
/Y.B./	AM	2000-339153	12/2000	JP			Abstract
	AN						

## OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

	AO	
	AP	
	AQ	

EXAMINER

/Yonas Bayou/

DATE CONSIDERED

01/02/2008

## INFORMATION DISCLOSURE STATEMENT

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)  
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## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/Y.B./	AA	6,049,670	4/2000	Okada et al.			
/Y.B./	AB	6,848,047	1/2005	Morikawa et al.			
/Y.B./	AC	5,751,805	5/1998	Otsuki et al.			
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	AI						

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/Y.B./	AJ	1 083 480	3/2001	EP			
/Y.B./	AK	6-87220	11/1994	JP			Abstract
	AL						
	AM						
	AN						

## OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

/Y.B./	AO	Bruce Schneier, John Wiley & Sons, Inc., "Applied Cryptography", 1996, pp. 34-41
	AP	
	AQ	

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